

# Osptek Display

## AMOLED SPECIFICATION

Model No:

**AM119Q390390FLS2**

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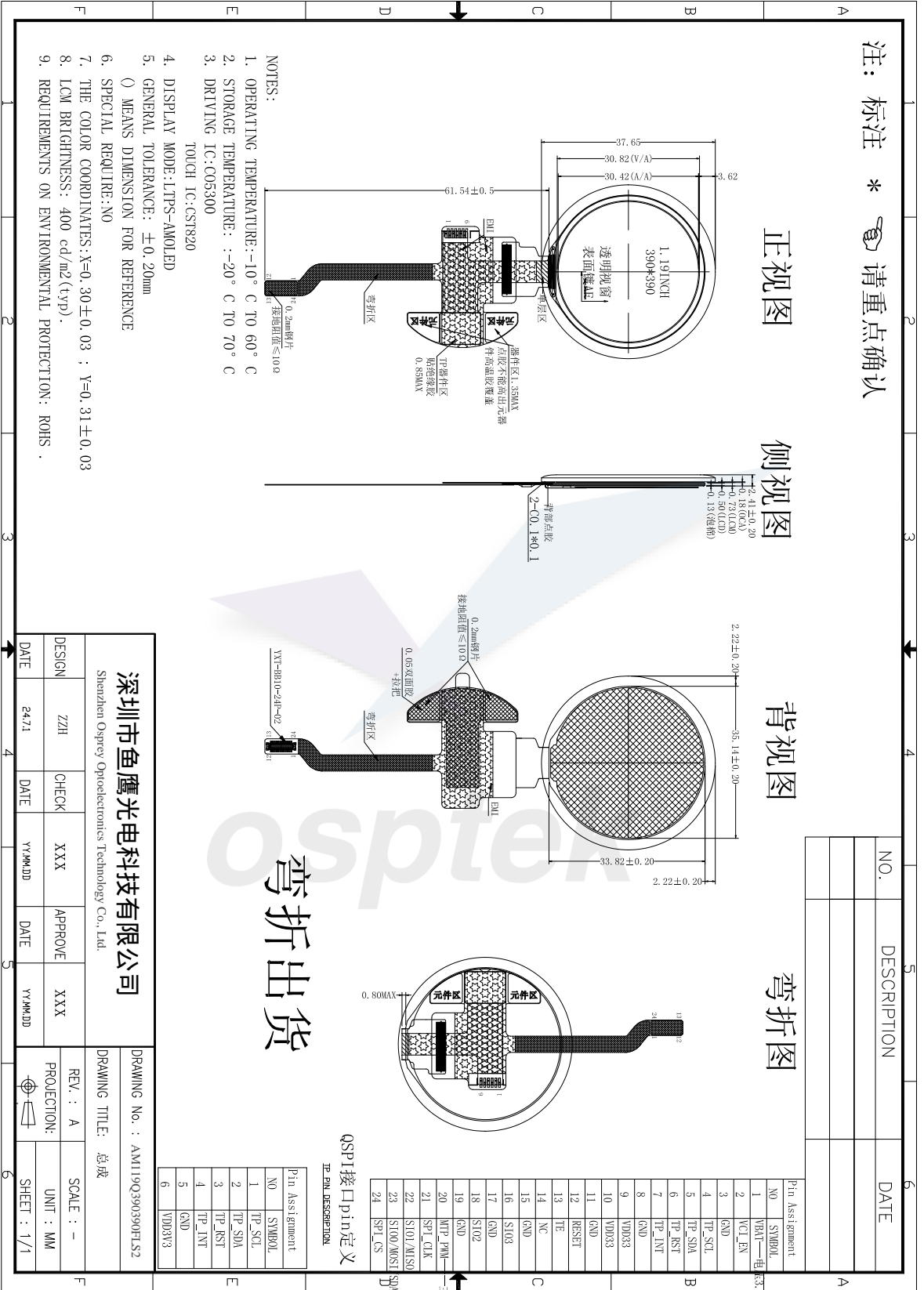
## 1.General Spec

Item	Standard values	Unit 单位
Diagonal Inch	1.19	inch
Dot arrangement	390(W) x RGB x 390(H)	dots
Pixel pitch	-	$\mu$ m
Display mode	AMOLED	/
Driver IC	CO5300	/
Module size	37.65(V) x 37.65(W) x 2.41(T)	mm
Active area	$\phi$ 30.42	mm
Interface	QSPI	-
Operating temperature	-10~60	°C
Storage temperature	-20~70	°C



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# 2.Mechanical drawing



### 3. Interface description

Pin No.	Symbol	Description
1	VBAT	Analog Power Input for POWER IC Input Voltage Range: 3.4V to 5.5V
2	VCI-EN	Enable for POWER IC
3	GND	Ground.
4	TPSCL	Touch Panel Clock
5	TPSDA	Touch Panel Data
6	TPRST	Touch Panel Reset
7	TPINT	Touch Panel interrupt
8	GND	Ground.
9	VDD	Power Supply for Analog Circuits VCI < 0.05V (When power is turned off)
10	VDD	Power Supply for Analog Circuits VCI < 0.05V (When power is turned off)
11	GND	Ground.
12	RESET	Device reset signal (0 : Enable ; 1: Disable )
13	TE	Tearing effect output pin to synchronize MCU to frame
14	NC	NC
15	GND	Ground.
16	SD3	Serial Data Input in Quad-SPI
17	GND	Ground.
18	SD2	Serial Data Input in Quad-SPI
19	GND	Ground.
20	MTP	External Voltage Input for OTP Data Program
21	SCL	Synchronous Clock Signal in MIPI DBI Type-B(MPU) and Type-C(SPI)
22	SD1	Serial Data Input in Quad-SPI
23	SD0	Serial Data Input in Quad-SPI
24	CS	Chip Select Signal in MIPI DBI Type-B(MPU) and Type-C(SPI)

## 4. Absolute Maximum Ratings

Item	Symbol	Min	Max	Unit
Supply voltage (Display)	VDD	-0.3	3.6	V
	IOVCC	-0.3	3.6	V
	VBAT	3.4	5.5	V
	VCI_EN	3.3		V
Operating temperature range	Top	-10	+60	°C
Storage temperature range	Tst	-20	+70	°C
Storage humidity	HD	-	90	%RH

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## 5. DC Characteristics

DC Characteristics List

Parameter	Symbol	Conditions	MIN	TYP	MAX	Unit	Notes
<b>Power generation &amp; Operation Voltage</b>							
AVDD booster voltage	AVDD	Operating Voltage	4.5	-	6.5	V	
VCL booster voltage	VCL	Operating Voltage	-5.0	-	-3.5	V	
Analog Operating voltage	VREFP	Operating Voltage	0.5	-	5.0	V	
Analog Operating voltage	VREFN	Operating Voltage	-5.0	-	-0.5	V	
Analog Operating voltage	I_ELVD	Operating Voltage	2.0	-	5.0	V	
Analog Operating voltage	I_ELVS	Operating Voltage	-5.4	-	-0.5	V	
Gamma reference voltage	VGMP	Operating Voltage	2	-	6.3	V	
Gamma reference voltage	VGSP	Operating Voltage	0	-	4.5	V	
VGH booster voltage	VGH	Operating Voltage	3	-	10.6	V	
VGL booster voltage	VGL	Operating Voltage	-15	-	-2	V	
Voltage difference between VGH and VGL	VGH-VGL	$ VGH-VGL  \leq 30$			30	V	
I/O operating voltage	VDDI	I/O supply voltage	1.65	-	3.3	V	
<b>LOGIC INPUT/ OUTPUT</b>							
Logic High level input voltage	V <sub>IH</sub>		$0.8 \times VDDI$	-	VDDI	V	1
Logic Low level input voltage	V <sub>IL</sub>		VSS	-	$0.2 \times VDDI$	V	1
Logic High level output voltage	V <sub>OH</sub>	I <sub>OH</sub> = -0.1mA	$0.8 \times VDDI$	-	VDDI	V	2
Logic Low level output voltage	V <sub>OL</sub>	I <sub>OL</sub> = +0.1mA	VSS	-	$0.2 \times VDDI$	V	2
Logic High level leakage	I <sub>LH1</sub>	V <sub>in</sub> = 0 to VDDI	-	-	1	μA	1,2
Logic Low level leakage	I <sub>LIL1</sub>	V <sub>in</sub> = 0 to VDDI	-1	-	-	μA	1,2
<b>Source OP Output</b>							
Output deviation voltage	V <sub>dev</sub>	S <sub>out</sub> ≅ 4.2V S <sub>out</sub> ≅ 0.8V			TBD	mV	4
Output deviation voltage	V <sub>dev</sub>	4.2V > S <sub>out</sub> > 0.8V			TBD	mV	
Output offset voltage	V <sub>OFFSET</sub>				TBD	mv	
<b>Stand-by Current</b>							
Sleep In mode	I <sub>stop</sub>	DSI LP mode VDDI Current		TBD		μA	
		DSI LP mode VCI Current		TBD		μA	1
	I <sub>stall</sub>	DSI Ultra Low power VDDI Current		TBD		μA	
		DSI Ultra Low power VCI Current		TBD		μA	1
<b>Oscillator Output</b>							
Oscillator tolerance	ΔOSC	All Temperature	-2%	-	2%	%	3

## 6. Electron-optical Characteristics

### 5.1 Electrical Characteristics

#### 5.1.1 Power Characteristic:

Item	Symbol	Min.	Typ.	Max.	Unit	Remark
AMOLED Power positive	ELVDD	-	-	-	V	-
AMOLED power Negative	ELVSS	-	-	-	V	Ref
Digital Power supply	VDDIO	1.7	1.8	1.95	V	Ref
Analog Power supply	VCI	3.25	3.3	3.35	V	Ref

#### 1) Normal Mode

**Power Supply:** IOVCC=1.8V VCI=3.3V

**Frame Frequency:**  $F_{frame} = 60\text{HZ}$  @ 25degC, Brightness 450 nits, Command Mode,

Display Condition	Symbol	Min.	Typ.	Max.	Unit	Remark
100% Pixel On 450nits	IELVDD /ELVSS	-	-	-	mA	Ref
	IVCI	-	6	7.2	mA	Ref
	IVDDIO	-	3	3.6	mA	Ref

#### 2) Idle Mode

**Power Supply:** IOVCC=1.8V VCI=2.8V

**Frame Frequency:**  $F_{frame} = 15\text{HZ}$  @ 25degC, Brightness:100nits, OPR:10%,Command Mode(driver ic fc power)

Display Condition	Symbol	Min.	Typ.	Max.	Unit	Remark
10% Pixel On 100 nits	IELVDD /ELVSS	-	-	-	mA	Supplied by Driver IC
	IVCI	-	5	6	mA	Ref
	IVDDIO	-	1.2	1.5	mA	Ref

#### 3) Deep Standby Mode

Display Condition	Symbol	Min.	Typ.	Max.	Unit	Remark
Deep Standby(Vci Off)	Power Consumpti on	-	-	<50	uW	Ref

Item	Symbol	Condition	Min	Typ	Max	Unit	Remark
Luminance (with Lens)	Normal mode Bp	$\Phi=0^\circ, \theta=0^\circ$	315	350	NA	cd/m <sup>2</sup>	Note1 Note2
Contrast Ratio	CR	$\Phi=0^\circ, \theta=0^\circ$	10000		-	-	Note3
Uniformity	$\Delta Bp$	Normal mode@W255 $\Phi=0^\circ, \theta=0^\circ$	70	-	-	%	Note4
Color Gamut	NTSC	CIE 1931	70		-	%	Note5
Response Time	T <sub>on</sub> Or T <sub>off</sub>	GL0-255	-	-	1	ms	Note6



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The optical characteristics should be measured in dark room. After 5 minutes operation, the optical properties are measured at the center point of the OLED screen. All input terminals OLED panel must be ground when measuring the center area of the panel.

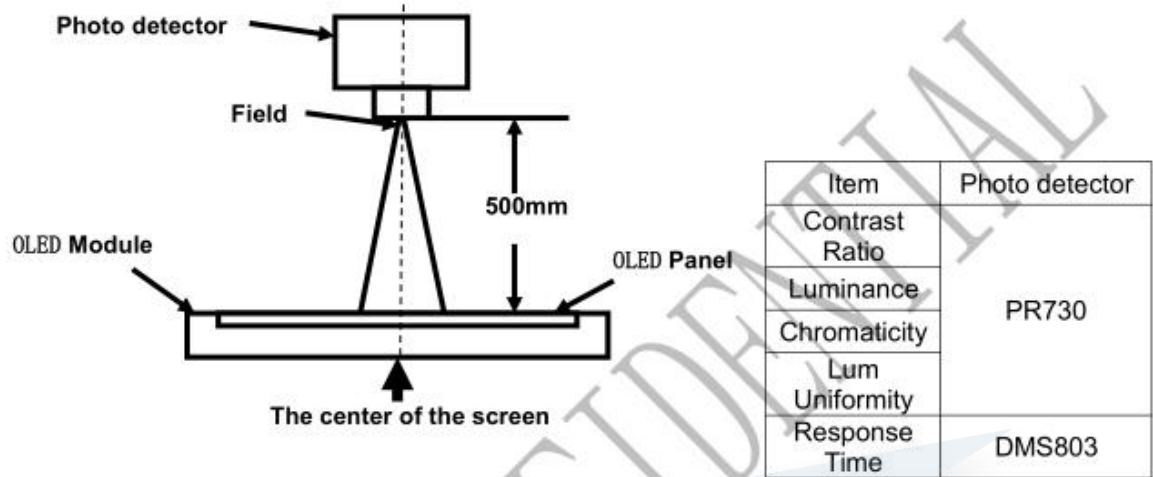
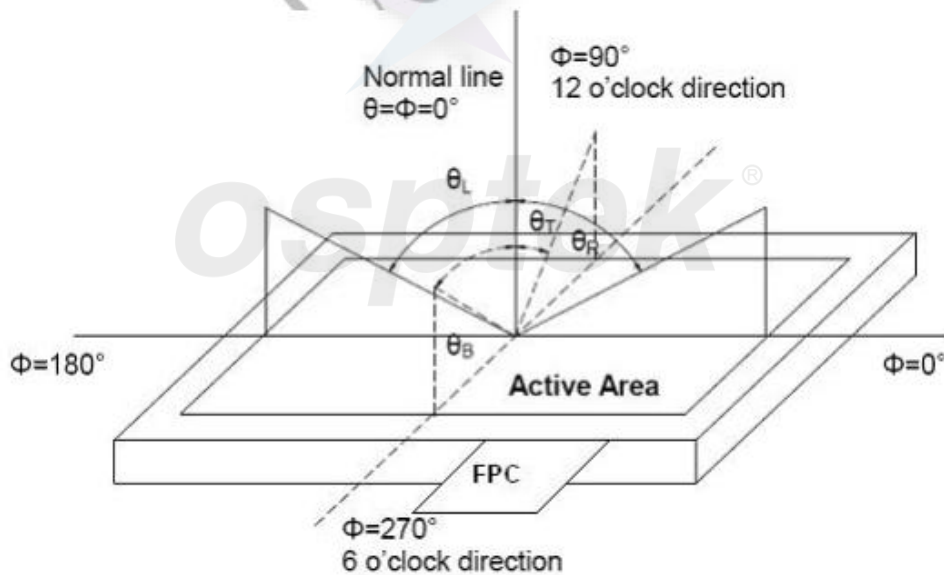


Fig. 1 Optical measurement system

Note 2: Definition of viewing angle range and measurement system. viewing angle is measured at the center point of the OLED by PR730.



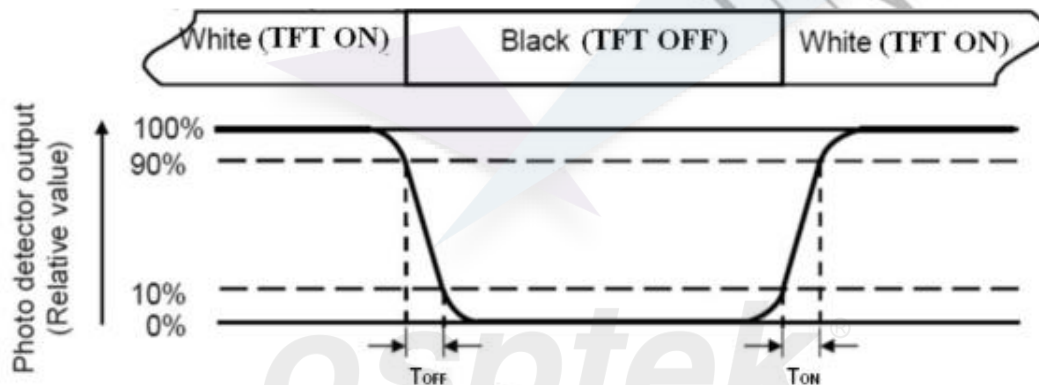
$$\text{Contrast ratio (CR)} = \frac{\text{Luminnace measured when OLED is on the "White" state}}{\text{Luminnace measured when OLED is on the "Black" state}}$$

"White state ":The state is that the OLED should be driven by  $V_{\text{white}}$ .

"Black state": The state is that the OLED should be driven by  $V_{\text{black}}$ .

#### Note 4: Definition of Response time

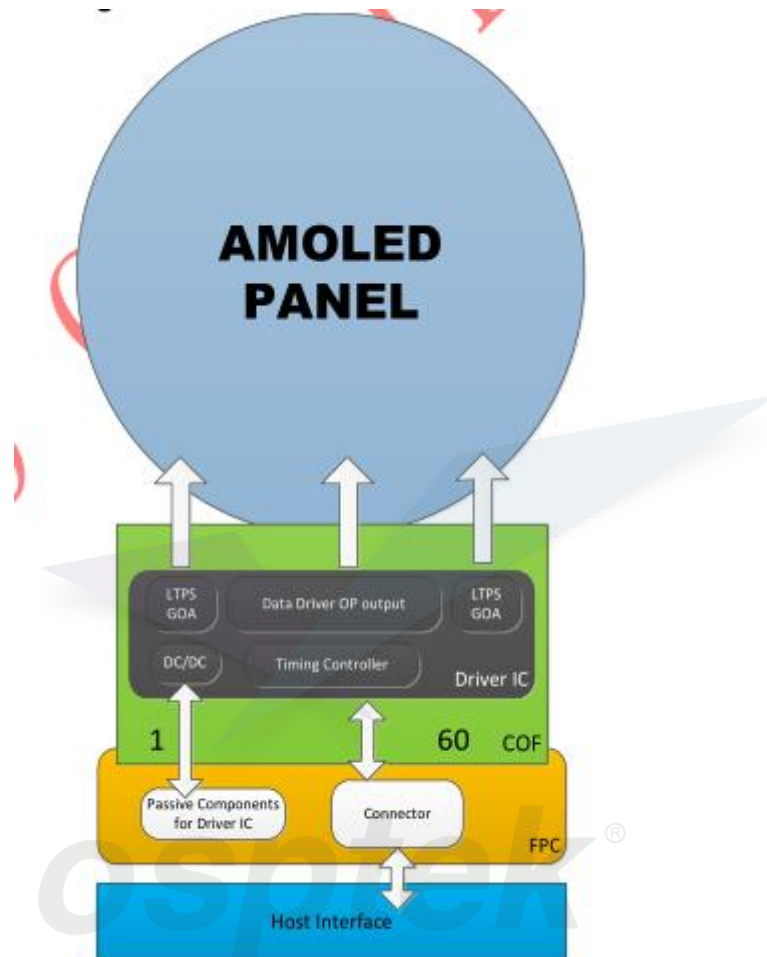
The response time is defined as the OLED optical switching time interval between "White" state and "Black" state. Rise time ( $T_{\text{ON}}$ ) is the time between photo detector output intensity changed from 90% to 10%. And fall time ( $T_{\text{OFF}}$ ) is the time between photo detector output intensity changed from 10% to 90%.



#### Note 5: Definition of color chromaticity (CIE1931)

Color coordinates measured at center point of OLED.

## 7. System Block Diagram



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## 8. AC characteristic

### QSPI write protocol

- QSPI Command/pixel write: 支持888/666/565/332/111/GRAY256 data format

#### 1 wire write



666/565/332格式支持补位方式:  
补MSB/补0/补1

#### 2 wire write



#### 4 wire write

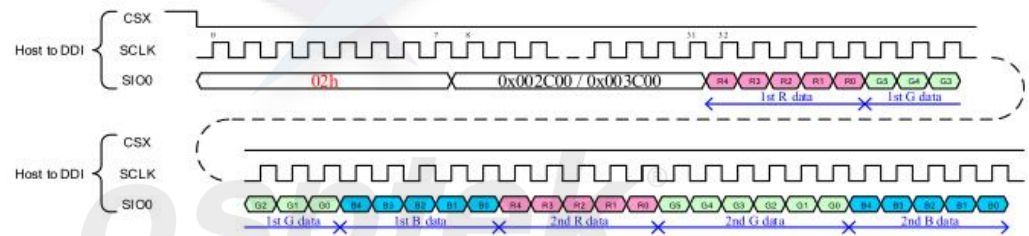


- QSPI Command/pixel read

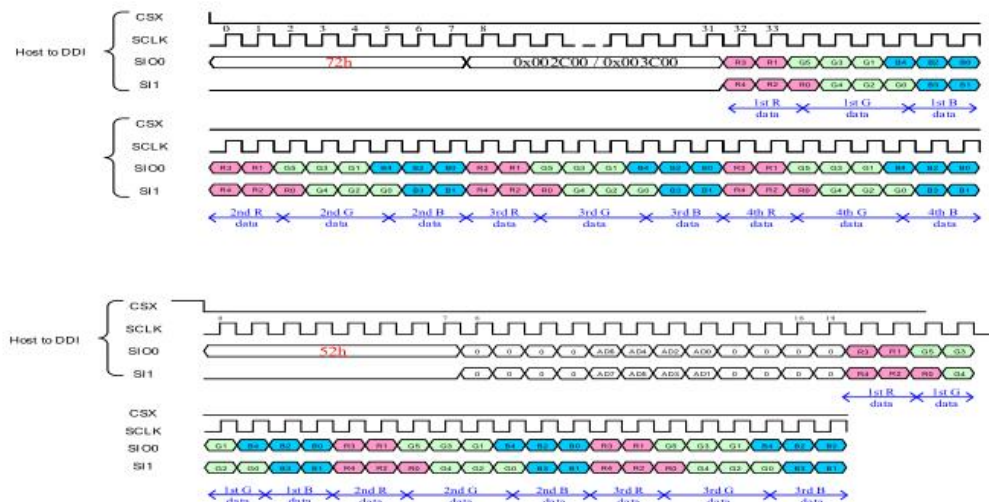


## QSPI Data format for RGB565

### 1 wire

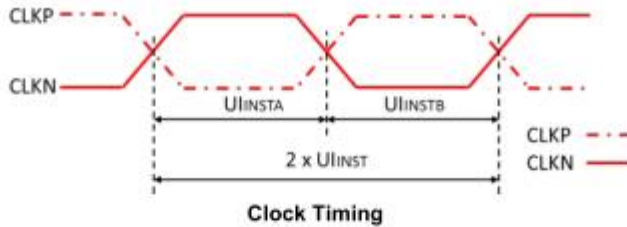


### 2 wire



**MIPI AC Characteristics**

**6.5.1 High Speed Mode - Clock Timings**

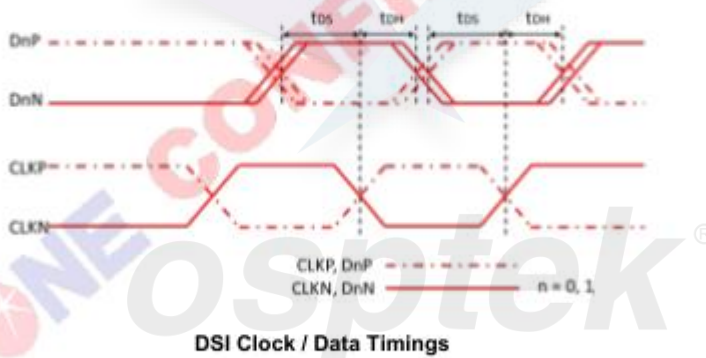


**High Speed Mode - Clock Timing**

Signal	Symbol	Parameter	Specification			Unit	Notes
			MIN	TYP	MAX		
CLK P/N	$2xUI_{INST}$	Double UI instantaneous	2		25	nS	
CLK P/N	$UI_{INSTA}, UI_{INSTB}$	UI instantaneous Half	4		12.5	nS	1

Note 1:  $UI = UI_{INSTA} = UI_{INSTB}$ .

**6.5.2 High Speed Mode - Clock / Data Timings**



**High Speed Mode - Clock / Data Timing**

Signal	Symbol	Parameter	Specification			Unit	Notes
			MIN	TYP	MAX		
Dn P/N (n=0, and 1)	tbs	Data to Clock Setup time	$0.15 \cdot UI$			UI	
	tch	Clock to Data Hold time	$0.15 \cdot UI$			UI	

## High Speed Mode - Rising and Falling Timings

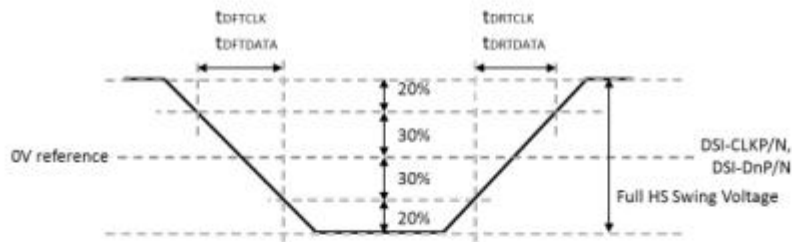


Figure 6-2 Rising and Falling Timings

### High Speed Mode - Rising and Falling Timing

Parameter	Symbol	Conditions	Specification			Unit	Notes
			MIN	TYP	MAX		
Differential Rise Time for Clock	tDRTCLK	CLKP/N	150pS		0.3*UI		2,3
Differential Rise Time for Data	tDRTDATA	DnP/N	150pS		0.3*UI		1,2,3
Differential Fall Time for Clock	tDFTCLK	CLKP/N	150pS		0.3*UI		2,3
Differential Fall Time for Data	tDFTDATA	DnP/N	150pS		0.3*UI		1,2,3

**Note 1:** DnP/N, n =0, and 1.

**Note 2:** The display module has to meet timing requirements, which are defined for the transmitter (MCU) on MIPI D-PHY standard.

**Note 3:** DSI-CLK+ = CLKP.

DSI-CLK- =CLKN.

DSI-D0+ =D0P.

DSI-D0- =D0N.

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## 10. Reliability test conditions and methods

No	Test Item	Test condition	Criterion
1	High Temperature Storage	70°C±3°C 48H Power off	Inspection after 4 hours storage at room temperature, the sample shall be free from defects: <ol style="list-style-type: none"> <li>1. Air bubble in the LCD;</li> <li>2. Seal leak;</li> <li>3. Non-display;</li> <li>4. missing segments;</li> <li>5. Glass crack;</li> <li>6. Current I<sub>dd</sub> is twice higher than initial value.</li> <li>7. The surface shall be free from damage.</li> <li>8. The electric characteristic requirements shall be satisfied</li> </ol>
2	Low Temperature Storage	-20°C±3°C 48H Power off	
3	High Temperature Operation	60°C±3°C 48H Power on	
4	Low Temperature Operation	-10°C±3°C 48H Power on	
5	High Temperature & Humidity Operation	60°C±3°C 90%RH 48H Power off	
6	Temperature Cycle	-10°C ↔ 25°C ↔ 60°C 30min 5min 30min 5 cycle Power off	

### Remark:

1. The test samples should be applied to only one test item.
2. Sample size for each test item is 3~5pcs.
3. For Damp Proof Test, Pure water (Resistance > 10MΩ) should be used.
4. In case of malfunction defect caused by ESD damage, if it would be recovered to normal state after resetting, it would be judged as a good part.
5. EL evaluation should be excepted from reliability test with humidity and temperature: Some defects such as black spot/blemish can happen by natural chemical reaction with humidity and Fluorescence EL has.
6. Failure Judgment Criterion: Basic Specification, Electrical Characteristic, Mechanical Characteristic, Optical Characteristic.